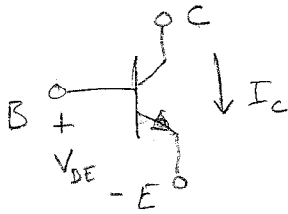


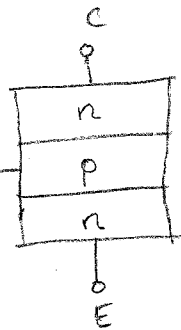
Review BJTs



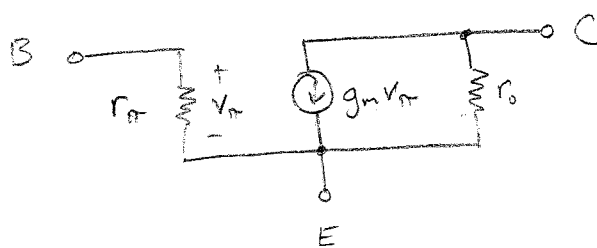
$$I_C = I_S e^{V_{BE}/V_T}$$

$$V_T = \text{thermal voltage} = \frac{k_B T}{q_e}$$

I_S = saturation current



Small signal model



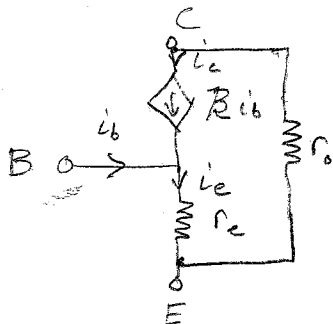
$$g_m = \frac{\partial I_C}{\partial V_{BE}} = I_S \frac{V_{BE}}{V_T} e^{V_{BE}/V_T} = \frac{I_C}{V_T}$$

$$r_o = \frac{V_A}{I_C}$$

V_A = Early voltage

$$r_{\pi} = \frac{\beta}{g_m}$$

Alternate model (equivalent)



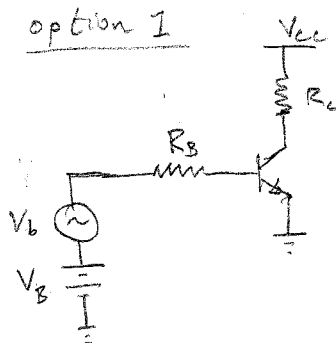
$$r_e = \frac{R}{\beta + 1} \cdot \frac{1}{g_m} \approx \frac{1}{g_m}$$

=> current controlled version

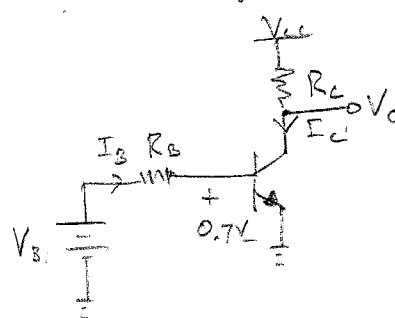
Common emitter amplifier (DC coupled)

Biasing

option 1



Large signal



$$I_B = \frac{V_B - 0.7V}{R_B}$$

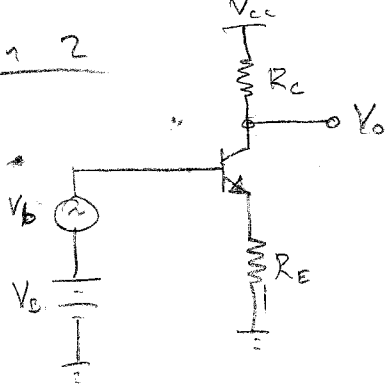
$$I_C = \beta I_B$$

$$V_o = V_{CC} - I_C R_C$$

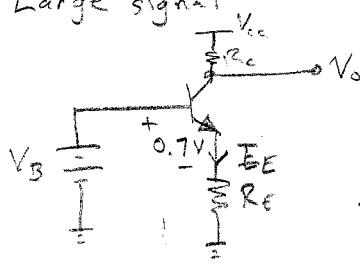
Problems?

- collector current set by β -> may not be a very stable quantity over temp, etc.
- resistive divider between R_B & r_{π} -> attenuates signal

option 2



Large signal



$$I_E = \frac{V_B - 0.7V}{R_E}$$

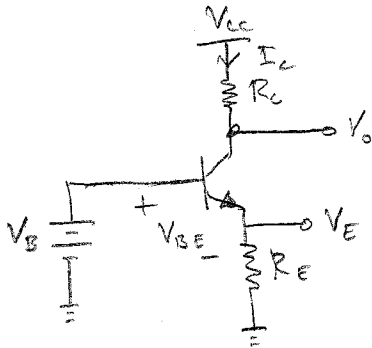
$$I_C \approx I_E$$

$$V_O = V_{CC} - R_C I_C$$

Advantage: I_C independent of R (assuming $\beta \gg 1$)
 No voltage division at input.

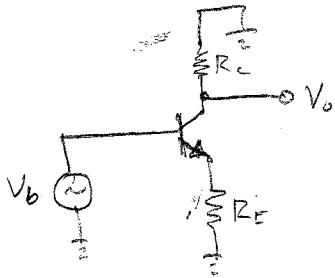
Known as emitter degeneration

- actually a feedback technique

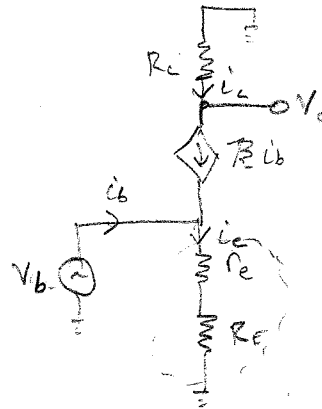


- If $I_C \uparrow \Rightarrow V_E \uparrow \Rightarrow V_{BE} \downarrow \Rightarrow I_C \downarrow$
- ensures stable I_C

Small signal



\Rightarrow



• r_e & R_E can be lumped together

$$i_e = \frac{V_{b_i}}{R_E + r_e}$$

$$\beta \rightarrow \infty$$

$$\Rightarrow i_c = i_e$$

$$V_o = -i_c R_C$$

$$= -i_e R_C$$

$$\boxed{\frac{V_o}{V_b} = -\frac{R_C}{R_E + r_e}}$$

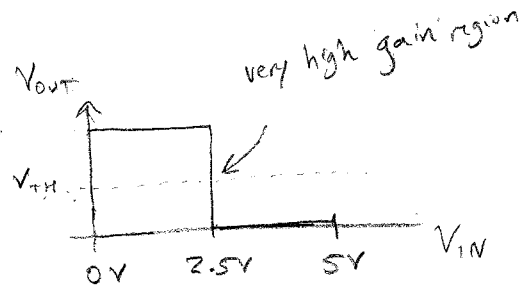
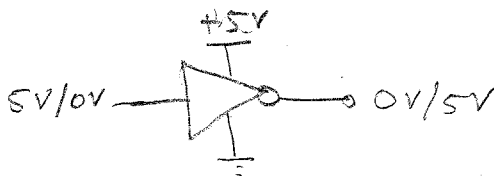
MOSFETs

Shortcomings of BJTs

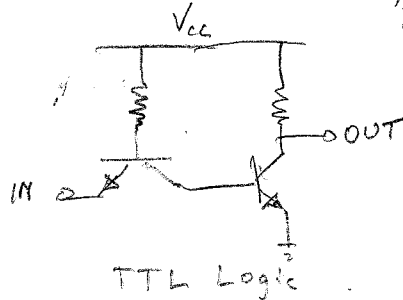
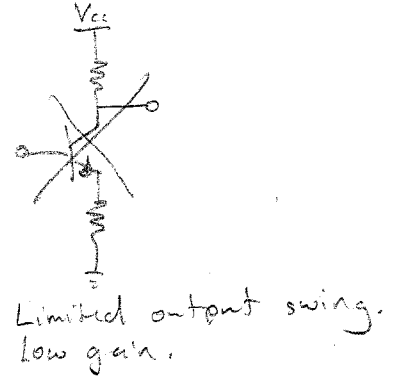
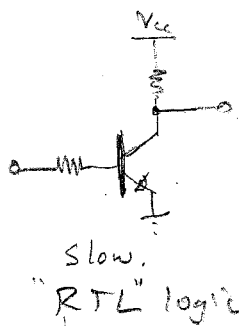
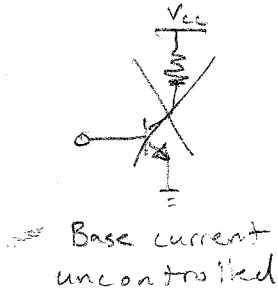
- Finite input resistance
- Require DC base current
- Incompatible with constant voltage base drive schemes (due to p-n junction between BE)

Application: Logic circuits

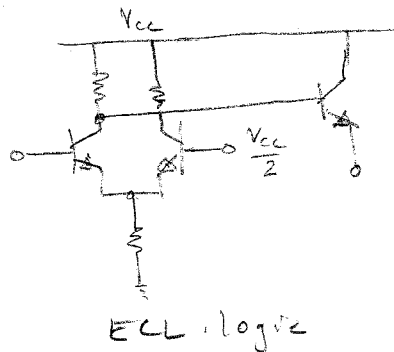
Inverter



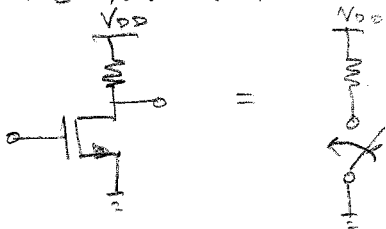
How can we make this with BJTs?



- All consume static power
- require resistors

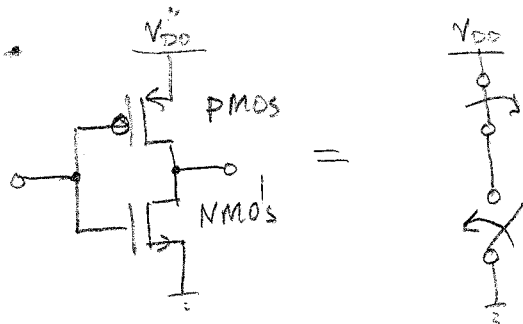


What if we had a true voltage controlled device?



- Input current = 0 (static)
- No current consumption when switch is open
- Input & output levels are compatible.

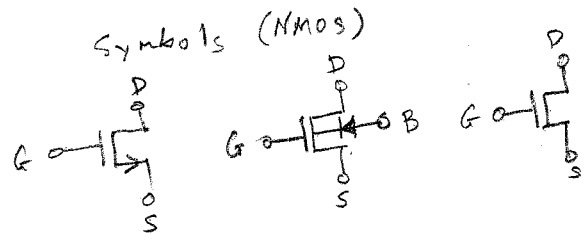
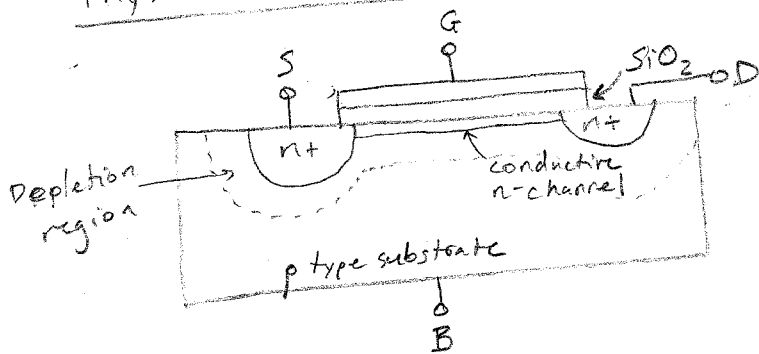
Complementary logic



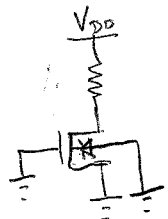
PMOS: on with 0 input
 NMOS: on with V_{DD} input

- Switches are never closed simultaneously
- No static power consumption
 - there is still dynamic power consumption associated with charging gate cap. (more later)

Physical device (NMOS)

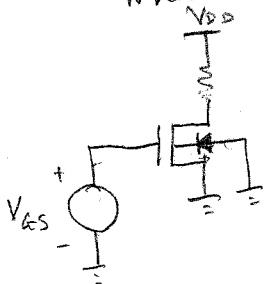


Idea: The conductivity of the channel (region under gate) is modulated by the gate to B/S/D voltage.



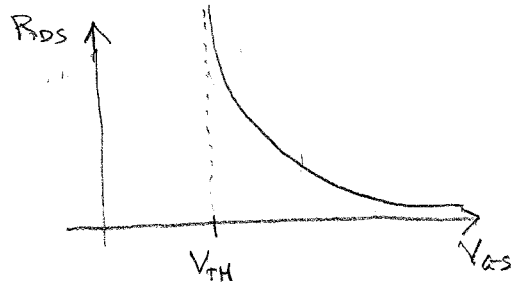
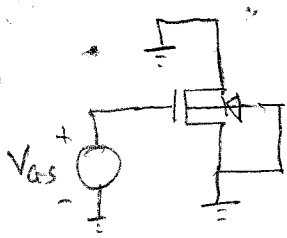
\Rightarrow No gate bias, no conductive channel between S & D. D/B form a reverse biased PN junction
 \therefore there is no drain current.

What happens if we apply bias?



1. Depletion region begins to form under gate. Holes are pushed downward, leaving behind a region of high (negative) space charge.
 2. After a critical point, a thin layer of electrons forms right under the gate, enabling current flow. \Rightarrow known as "inversion"
- critical point = threshold voltage

The FET as a controlled resistor



$$R_{on} = \frac{1}{\mu_n C_{ox} \frac{W}{L} (V_{gs} - V_{TH})} \quad (6.12)$$

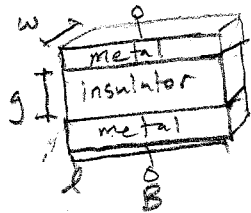
- ① μ_n = electron mobility [$\frac{cm^2}{Vs}$] Note: v_e = electron drift velocity = $\mu_n E$
↑
electric field
- ② C_{ox} = Gate to channel capacitance per unit area [$\frac{F}{m^2}$]
- ③ W = device width [m]
- ④ L = channel length [m]
- ⑤ V_{TH} = threshold voltage [V]

① • determined by doping, materials.

• no control by circuit designer

② $C_{ox} = \frac{\epsilon_{ox}}{t_{ox}} = \frac{\text{permittivity of dielectric}}{\text{thickness of gate oxide}}$

Review: parallel plate capacitor



$$C = \frac{\epsilon A}{g}, \quad A = wl$$

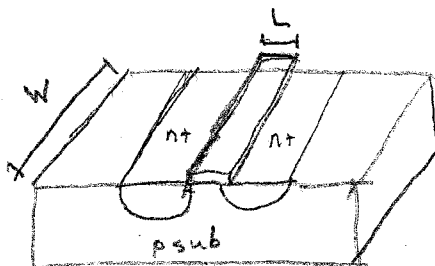
Physics: $D = \epsilon E$ (Maxwell's equation)

$$= \epsilon \frac{V}{g}$$

$$Q = DA = \frac{\epsilon A}{g} V$$

$$C = \frac{Q}{V} = \frac{\epsilon A}{g}$$

③ + ④



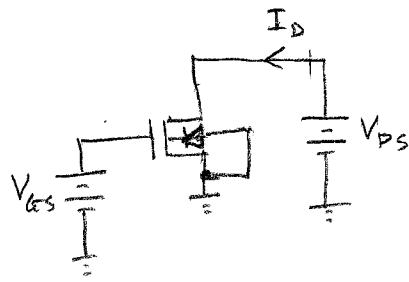
$$W \uparrow, L \downarrow \Rightarrow R_{DS} \downarrow$$

⑤ Roughly twice the Fermi Voltage. controlled by doping.

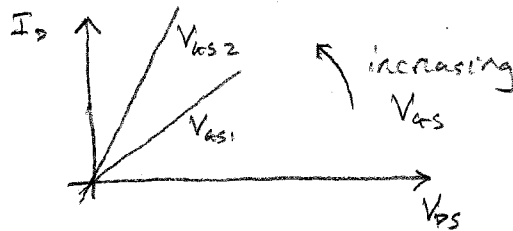
• No direct ckt. designer control, but typically high & low V_{TH} devices are available.

The FET as a current source. (pinch off effect)

What happens when we apply D to S voltage?

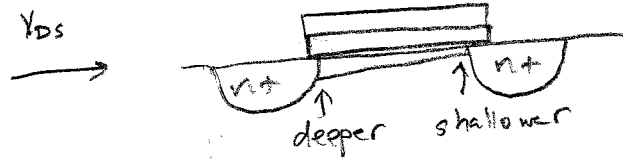
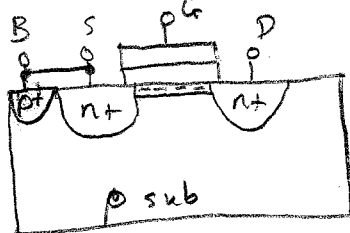


For small $V_{DS} \Rightarrow$ resistive operation

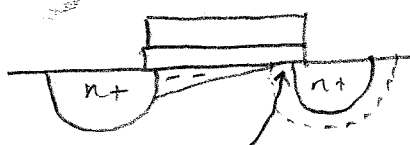


How small?

- MOSFETs are symmetric
- We assumed constant channel depth from D to S



- When $V_{GD} < V_{TH}$, the channel pinches off



Device still conducts because of very high Electric field in this region.

Rearrange this equation

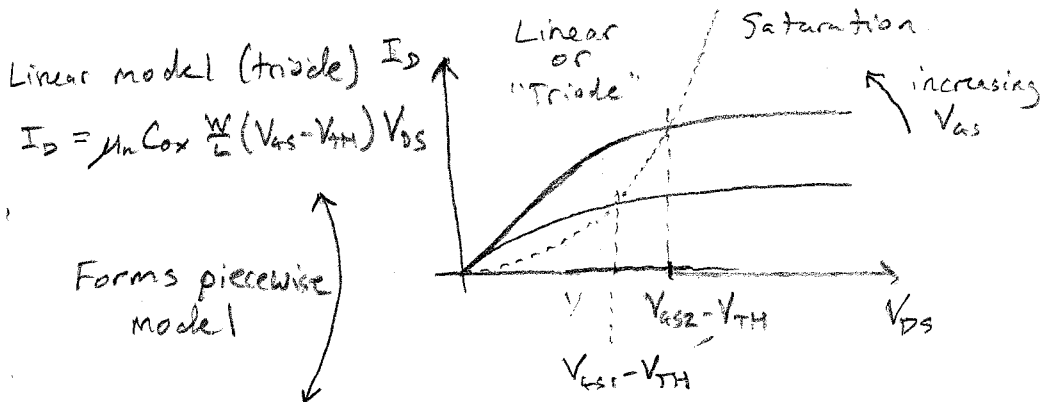
$$V_{GD} < V_{TH}$$

$$V_G - V_D < V_{TH}$$

$$V_D > V_G - V_{TH}$$

$$V_D - V_S > V_G - V_S - V_{TH}$$

"Saturation" condition: $V_{DS} > V_{GS} - V_{TH}$

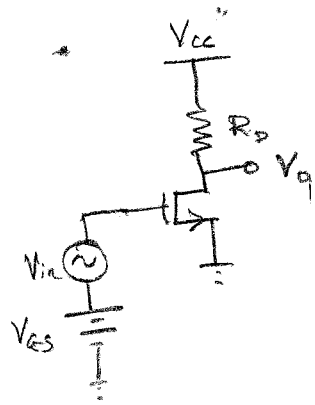


Notes:

- $I_{D,sat}$ still has slight dependence on $V_{DS} \Rightarrow$ ch. length mod. (more later)

Square Law model (saturation): $I_{D,sat} \approx \frac{1}{2} \mu_n C_{ox} \frac{W}{L} (V_{GS} - V_{TH})^2 \quad (V_{DS} > V_{GS} - V_{TH})$

The MOSFET as an amplifier (common source)



• Assume $V_{DS} > V_{GS} - V_{TH}$ (saturation)

$$I_D = \frac{1}{2} \mu_n C_{ox} \frac{W}{L} (V_{GS} + V_{in} - V_{TH})^2$$

$$\frac{\partial I_D}{\partial V_{in}} = \mu_n C_{ox} \frac{W}{L} (V_{GS} + V_{in} - V_{TH})$$

$$V_{in} \ll V_{GS} - V_{TH} \Rightarrow \frac{\partial I_D}{\partial V_{in}} = \mu_n C_{ox} \frac{W}{L} V_{ov}$$

V_{ov} = overdrive voltage

tells you how "on" the transistor is.

$$g_m = \frac{\partial I_D}{\partial V_{in}} = \text{small signal transconductance}$$

$$V_o = V_{o,DC} + v_o = V_{CC} - I_{D,sat} \cdot R_D - g_m V_{in} \cdot R_D$$

$$\text{Small signal gain} = \frac{\partial v_o}{\partial V_{in}} = -g_m R_D$$

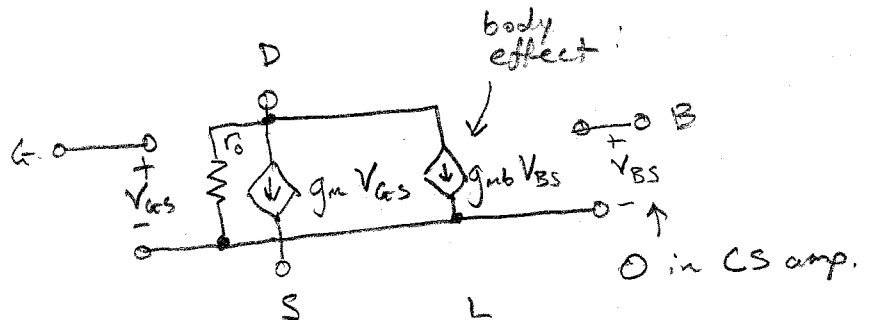
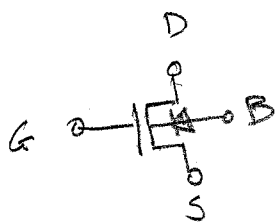
* Linearity is a big assumption.

Always remember where these equations come from, a Taylor series representation of the large signal model.

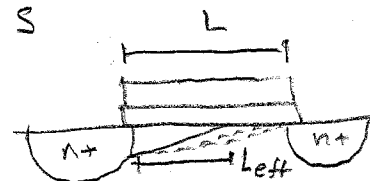
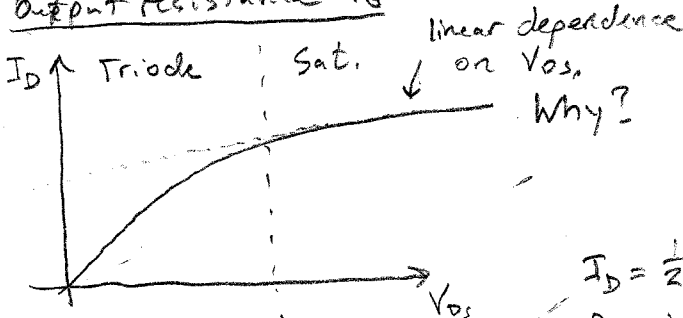
$$\text{Ex. } I_D = \frac{1}{2} \mu_n C_{ox} \frac{W}{L} (V_{GS} - V_{TH})^2$$

Calc. Taylor series about $V_{GS} = V_{GS0}$, drop high order terms.

Small signal model (DC)



output resistance r_o

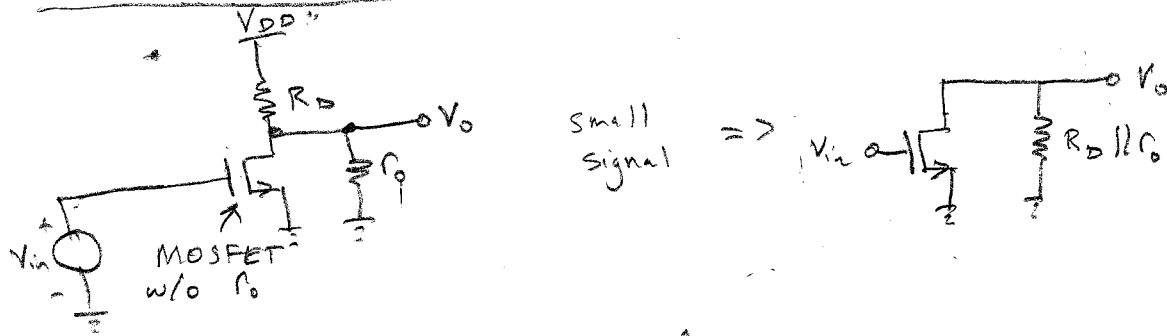


- Depending on V_{DS} , pinch off point will move
- Effectively modulates ch. length

$$I_D = \frac{1}{2} \mu_n C_{ox} \frac{W}{L} (V_{GS} - V_{TH})^2 (1 + \lambda V_{DS})$$

λ = ch. length mod. parameter

Impact of Ch. length mod



- C_o limits voltage gain of FET.
- Let $R_D \rightarrow \infty \Rightarrow a \rightarrow -g_m r_o$
- High voltage gains useful for:
 - minimizing steady state error in op-amp based ctrl. circuits.
 - improving linearity of feedback circuits
 - boosting signal levels for interfacing with ADC, for example.